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Volume 16

Table of Contents

Articles

Recovery of Marginal Maximum Likelihood Estimates in the Two-Parameter Logistic Response Model: An Evaluation of MULTILOG	<i>Clement A. Stone</i>	1
Analyzing Test Content Using Cluster Analysis and Multidimensional Scaling	<i>Stephen G. Sireci and Kurt F. Geisinger</i>	17
The Effect of Review on Student Ability and Test Efficiency for Computerized Adaptive Tests	<i>Mary E. Lunz, Betty A. Bergstrom, and Benjamin D. Wright</i>	33
Item Selection Using an Average Growth Approximation of Target Information Functions	<i>Richard M. Luecht and Thomas M. Hirsch</i>	41
Methods and Models for the Construction of Weakly Parallel Tests	<i>Jos J. Adema</i>	53
Computerized Mastery Testing With Nonequivalent Testlets	<i>Kathleen Sheehan and Charles Lewis</i>	65
Estimating Individual Rater Reliabilities	<i>John E. Overall and Kevin N. Magee</i>	77
Equating Tests Under the Graded Response Model	<i>Frank B. Baker</i>	87
Seriation and Multidimensional Scaling: A Data Analysis Approach to Scaling Asymmetric Proximity Matrices	<i>Joseph Lee Rodgers and Tony D. Thompson</i>	105
Replication as a Rule for Determining the Number of Clusters in Hierarchical Cluster Analysis	<i>John E. Overall and Kevin N. Magee</i>	119
A Conceptual Analysis of Differential Item Functioning in Terms of a Multidimensional Item Response Model	<i>Gregory Camilli</i>	129
A Method for Investigating the Intersection of Item Response Functions in Mokken's Nonparametric IRT Model	<i>Klaas Sijtsma and Rob R. Meijer</i>	149
A Generalized Partial Credit Model: Application of an EM Algorithm	<i>Eiji Muraki</i>	159
The Knowledge or Random Guessing Model for Matching Tests	<i>A. H. G. S. van der Ven and F. M. Gremmen</i>	177
Test of the Hypothesis That the Intraclass Reliability Coefficient is the Same for Two Measurement Procedures	<i>Yousef M. Alsawalmeh and Leonard S. Feldt</i>	195

A Review of Regression Diagnostics for Behavioral Research	<i>Sangit Chatterjee and Mustafa Yilmaz</i>	209
Correlated Effects in Generalizability Studies	<i>Philip L. Smith and Richard M. Luecht</i>	229
Multidimensionality and Item Bias in Item Response Theory	<i>T. C. Oshima and M. David Miller</i>	237
Using the Extreme Groups Strategy When Measures Are Not Normally Distributed	<i>Robert L. Fowler</i>	249
Measuring the Difference Between Two Models	<i>Michael V. Levine, Fritz Drasgow, Bruce Williams, Christopher McCusker, and Gary L. Thomasson</i>	261
Unidimensional Calibrations and Interpretations of Composite Traits for Multidimensional Tests	<i>Richard M. Luecht and Timothy R. Miller</i>	279
A Constrained PARAFAC Method for Positive Manifold Data	<i>Wim P. Krijnen and Jos M. F. Ten Berge</i>	295
The Ordered Partition Model: An Extension of the Partial Credit Model	<i>Mark Wilson</i>	309
The Nominal Response Model in Computerized Adaptive Testing	<i>R. J. De Ayala</i>	327
The Effect of Test Length and IRT Model on the Distribution and Stability of Three Appropriateness Indexes	<i>Brian W. Noonan, Marvin W. Boss, and Marc E. Gessaroli</i>	345
Effects of Response Format on Diagnostic Assessment of Scholastic Achievement	<i>Menucha Birenbaum, Kikumi K. Tatsuoaka, and Yaffa Gutvitz</i>	353
Polynomial Algorithms for Item Matching	<i>Ronald D. Armstrong and Douglas H. Jones</i>	365
Testing Hypotheses About Methods, Traits, and Communalities in the Direct-Product Model	<i>Richard P. Bagozzi and Youjae Yi</i>	373
Effect of Sample Size, Number of Biased Items, and Magnitude of Bias on a Two-Stage Item Bias Estimation Method	<i>M. David Miller and T. C. Oshima</i>	381
Inferential Conditions in the Statistical Detection of Measurement Bias	<i>Roger E. Millsap and William Meredith</i>	389
Book Reviews		
<i>Statistical Methods in Longitudinal Research</i> by Alexander Von Eye (Ed.)		
<i>Volume I: Principles and Structuring Change</i>	<i>Reviewed by A. T. Panter</i>	97
<i>Volume II: Time Series and Categorical Longitudinal Data</i>	<i>Reviewed by Robert Terry</i>	99

<i>Ratio Scaling of Psychological Magnitude</i> by Stanley J. Bolanowski, Jr. and George A. Gescheider (Eds.)	<i>Reviewed by Nancy A. Perrin</i>	101
<i>Multidimensional Scaling: Concepts and Applications</i> by P. E. Green, F. J. Carmone, Jr., and S. M. Smith	<i>Reviewed by Robert M. Hamer</i>	206
<i>An Introduction to the Logic of Psychological Measurement</i> by Joel Michell	<i>Reviewed by Paul Thompson</i>	306
<i>Best Methods for the Analysis of Change</i> by Linda M. Collins and John L. Horn (Eds.)	<i>Reviewed by Jan de Leeuw</i>	403
Computer Program Exchange		
IRTDATA: An Interactive or Batch Pascal Program for Generating Logistic Item Response Data	<i>George A. Johanson</i>	52
PERMUTE: A SAS Algorithm for Permutation Testing	<i>Jeffrey D. Kromrey, Walter M. Chason, and R. Clifford Blair</i>	64
A__STAT: Statistical Hypotheses and Utilities (Version 2.0)	<i>John R. Reddon</i>	86
IRTDIF: A Computer Program for IRT Differential Item Functioning Analysis	<i>Seock-Ho Kim and Allan S. Cohen</i>	158
DIMTEST: A Fortran Program for Assessing Dimensionality of Binary Item Responses	<i>William Stout, Ratna Nandakumar, Brian Junker, Hua-Hua Chang, and Duane Steidinger</i>	236
TESTINFO: A Graphics-Oriented Program for Selecting Items for Target Test Information and Standard Error or Measurement Curves	<i>John H. Neel</i>	260
A SAS Macro Program for Applications of Five Bonferroni Type Methods	<i>Jianmin Li, Weiming Luh, and Stephen Olejnik</i>	364
Volume 16 Author and Subject Index		407

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